IN THE CLAIMS:

Claims 2-8, 10, and 12-17 have been amended herein. All of the pending claims 1 through 17 are presented below. This listing of claims will replace all prior versions and listings in the application. Please enter these claims as amended.

- 1. (Original) A semiconductor device formed by a laser etching process comprising: providing a substrate having a surface; forming resist on at least a portion of the surface; and etching the resist from the surface of the substrate using a laser.
- 2. (Currently Amended) The method according to claim 1, wherein-said the laser comprises a laser associated with an automolding system.
- 3. (Currently Amended) The method according to claim 1, wherein-said the laser includes one of an Nd:YAG laser and an excimer laser.
- 4. (Currently Amended) The method according to claim 1, wherein-said the substrate comprises a ball-grid-array substrate.
- 5. (Currently Amended) The method according to claim 1, further comprising a vision system for detecting resist the resist.
- 6. (Currently Amended) The method according to claim 5, wherein-said the vision system comprises:

 providing a laser scanning system; and detecting changes in a pattern of the substrate.

- 7. (Currently Amended) A method of enhancing the adhesion of a compound to a surface of a substrate comprising: providing-said the substrate having-said the surface; and roughening the surface of the substrate.
- 8. (Currently Amended) The method according to claim 7, wherein said-roughening comprises removing contamination and foreign particles from-said the surface of the substrate.
- 9. (Original) An automolding system comprising: providing a substrate having a surface; preheating the substrate; forming a resist layer; baking the substrate; and removing contaminants from the substrate using a laser.
- 10. (Currently Amended) The automolding system of claim 9, wherein-said the laser comprises one of an Nd:YAG laser and an excimer laser.
- 11. (Original) The automolding system of claim 9, further comprising: placing the substrate in a mold; and encapsulating the substrate.
- 12. (Currently Amended) A semiconductor device formed by a laser etching process on a substrate having a surface comprising: forming resist on at least a portion of the surface; and etching the resist from the at least a portion of the surface of the substrate using a laser.

- 13. (Currently Amended) The method according to claim 12, wherein-said the laser comprises a laser associated with an automolding system.
- 14. (Currently Amended) The method according to claim 12, wherein-said the laser includes one of an Nd:YAG laser and an excimer laser.
- 15. (Currently Amended) The method according to claim 12, wherein-said the substrate comprises a ball-grid-array substrate.
- 16. (Currently Amended) The method according to claim 12, further comprising a vision system for detecting resist the resist.
- 17. (Currently Amended) The method according to claim 16, wherein-said the vision system comprises:

 providing a laser scanning system; and detecting changes in a pattern of the substrate.